

10/666,770

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	boundary scan test receiver\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 12:54
L2	3	boundary scan test receiver\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 12:55
L3	405475	comparator	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 12:55
L4	2	I2 and I3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 12:55
L5	27	programmable hysteresis circuit	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 12:55
L6	2	I4 and I5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:13
L7	181868	reference voltage	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 12:56
L8	996	voltage hysteresis	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 12:56

EAST Search History

L9	403	I8 and I7	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 12:56
L10	5	I9 and I5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:06
L11	2	I10 and I2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:13
L12	2	I11 and I3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 12:56
L16	1	("IEEE 1149.6") and (boundary scan test)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:15
L17	4	("IEEE 1149.6 standard")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:14
L18	1142	(boundary scan test)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:14
L19	0	I17 and I18	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:14

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L21	3	I18 and I9	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:15
L22	2	I18 and I10	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:15
L23	13	("IEEE 1149.6")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:15
L25	5	I23 and (I18 or I17 or I9)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:52
L26	5244	714/727 or 714/724 or 714/736 or 327/205 or 327/63 or 327/73 or 327/68	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:56
L27	3	I25 and I26	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 14:05
L30	2	I10 and I18	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 13:58
L32	1	I18 and (I16 or I17 or I23)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 14:07

EAST Search History

L33	1	"IEEE 1449.6 boundary scan test"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/07/22 14:09
-----	---	----------------------------------	---	-----	----	------------------

10/666,770



Welcome United States Patent and Trademark Office

[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Help](#)[Search Session History](#)[BROWSE](#)[SEARCH](#)[IEEE Xplore GUIDE](#)

Sat, 22 Jul 2006, 2:28:44 PM EST

Edit an existing query or compose a new query in the Search Query Display.

Select a search number (#) to:

- Add a query to the Search Query Display
- Combine search queries using AND, OR, or NOT
- Delete a search
- Run a search

Search Query Display**Recent Search Queries**

- | | |
|----|--|
| #1 | IEEE boundary scan test |
| #2 | ((ieee 1149.6 boundary scan test)<in>metadata) <and> (pyr >= 1950 <and> pyr <= 2003) |
| #3 | ((ieee 1149.6 and boundary scan test)<in>metadata) |
| #4 | ((ieee 1149.6 and boundary scan test)<in>metadata) |
| #5 | ((ieee 1149.6 and boundary scan test)<in>metadata) |
| #6 | ((ieee 1149.6 and boundary scan test)<in>metadata) |
| #7 | ((((ieee 1149.6 and boundary scan test)<in>metadata)) <and> (pyr >= 1950 <and> pyr <= 2003)) |

[Help](#) [Contact Us](#) [Privacy](#)

© Copyright 2006 IEEE

Indexed by
 Inspec®